## Application/Control No. Applicant(s)/Patent Under Reexamination 10/619,956 MEIER ET AL. Notice of References Cited Art Unit Examiner Page 1 of 1 1772 Patricia L. Nordmeyer **U.S. PATENT DOCUMENTS** Document Number Country Code-Number-Kind Code Date Classification Name MM-YYYY 222/105 US-3,696,969 10-1972 De Van et al. Α US-В US-С US-D US-Ε US-F US-G US-US-1 US-J US-Κ US-L US-М **FOREIGN PATENT DOCUMENTS** Document Number Date Country Name Classification Country Code-Number-Kind Code MM-YYYY Ν 0 Р Q R S Т **NON-PATENT DOCUMENTS** Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) U W

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